

BFP740ESD

**BFP740ESD ESD-Hardened SiGe:C
Ultra Low Noise RF Transistor with
2kV ESD Rating in 5–6GHz LNA
Application. 15dB Gain, 1.3dB Noise
Figure & < 100ns Turn-On / Turn-Off
Time**

**For 802.11a & 802.11n “MIMO”
Wireless LAN Applications**

Application Note AN219

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Page	Subjects (major changes since last revision)

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1 Overview

The BFP740FESD is a high gain, ultra low noise Silicon-Germanium-Carbon (SiGe:C) HBT device suitable for a wide range of Low Noise Amplifier (LNA) applications. The BFP740FESD has internal ESD-protection structures giving an ESD-survival rating of 2000 Volts per the Human Body Model (HBM), for ESD strikes of either polarity applied across any pair of terminals (Base, Emitter, Collector).

The circuit shown in this document is targeted for 802.11a & 802.11n "MIMO" applications in the Wireless Local Area Network (WLAN) market, particularly for Access Points (AP's) which require external LNA's to fulfill high-sensitivity / long range requirements. LNA's for this application must be able to switch on / off within about 1 microsecond (1000 nanoseconds). The charge storage (capacitance) used in the circuit is minimized to reduce turn-on / turn-off times. Trade-off for reduced capacitance values is a reduction in Third Order Intercept (IP3) performance. Amplifier is Unconditionally Stable ($\mu_1 > 1.0$) from 10 MHz – 12 GHz.

External parts count (not including BFP740 transistor) = 12; 6 capacitors, 3 resistors, and 3 chip inductors. All passives are '0402' case size. BFP740ESD transistor package is RoHS – compliant, industry-standard SOT343 type.

2 Typical Measurement Results

Table 1 Electrical Characteristics (at room temperature)

Parameter	Symbol	Value	Unit	Comment/Test Condition
Frequency	Freq	5.470	GHz	
DC Voltage	Vcc	3.0	V	
DC Current	Icc	14.7	mA	
Gain	G	15.5	dB	Network analyzer source power = -25 dBm
Noise Figure	NF	1.3	dB	Does not extract PCB loss. If PCB loss at input were extracted, NF would be ~0.2 dB lower
Input Return Loss	RLin	17.8	dB	Network analyzer source power = -25 dBm
Output Return Loss	RLout	23.9	dB	Network analyzer source power = -25 dBm
Reverse Isolation	IRev	20.3	dB	Network analyzer source power = -25 dBm When DC Power to LNA is OFF: 14.8dB
Input P1dB	IP1dB	-6.4	dBm	
Output P1dB	OP1dB	8.1	dBm	
Input IP3	IIP3	7.2	dBm	Input power -23dBm / tone, $\Delta f = 1\text{MHz}$
Output IP3	OIP3	22.7	dBm	Input power -23dBm / tone, $\Delta f = 1\text{MHz}$

3 Schematic Diagram

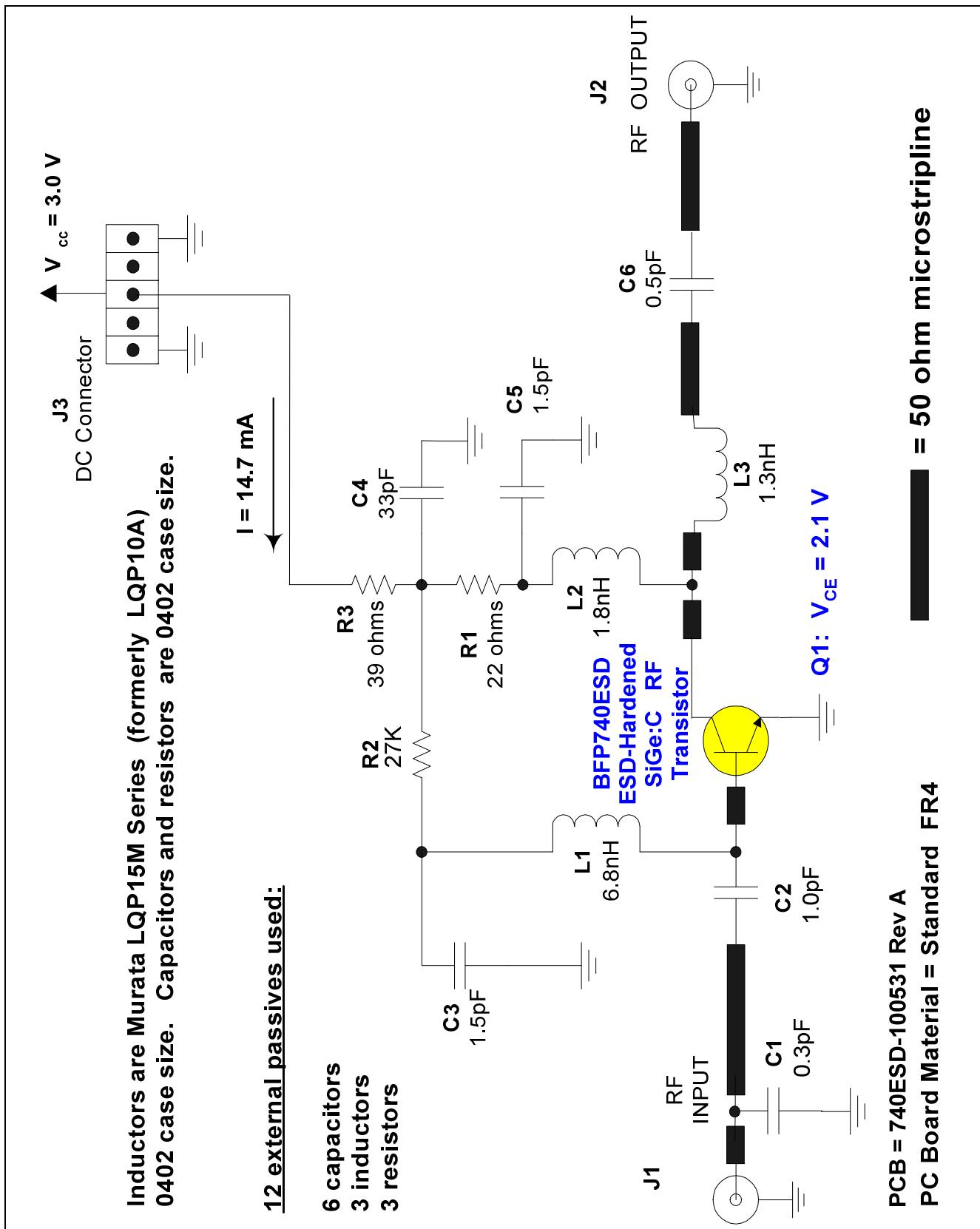


Figure 1 Schematic Diagram

4 Bill of Material

Table 2 Bill-of-Materials

Symbol	Value	Unit	Size	Manufacturer	Comment
C1	0.3	pF	0402	Murata GRM1555C1HR30BZ01D or equivalent	Input matching
C2	1.0	pF	0402	various	Input DC block, input matching
C3	1.5	pF	0402	various	RF decoupling / blocking cap
C4	33	pF	0402	various	RF decoupling / blocking cap
C5	1.5	pF	0402	various	RF decoupling / blocking cap
C6	0.5	pF	0402	Murata GRM1555C1HR30BZ01D or equivalent	Output DC block and output matching. Also influences input match.
L1	6.8	nH	0402	Murata LQP15M series	RF Choke at LNA input (for DC bias to base).
L2	1.8	nH	0402	Murata LQP15M series	RF Choke at LNA output, for DC bias to collector. Also influences matching and stability.
L3	1.3	nH	0402	Murata LQP15M series	Output matching; also influences input match.
R1	22	Ω	0402	various	For RF stability improvement
R2	27	$k\Omega$	0402	various	DC biasing (base).
R3	39	Ω	0402	various	DC biasing (provides DC negative feedback to stabilize DC operating point over temperature variation, transistor h_{FE} variation, etc.)
Q1	BFP740ESD	TSFP-4		Infineon Technologies	LNA active device
J1, J2	RF Edge Mount SMA Female Connector, 142-0701-841			Emerson / Johnson	Input / Output RF connector
J3	MTA-100 Series 5 pin connector 640456-5			Tyco (AMP)	5 Pin DC connector header
---	PC Board, Part # 740ESD- 100531 Rev A			Infineon Technologies	Printed Circuit Board

5 Measured Graphs

The reference plane of all data displayed here are the input and output SMA connectors of the evaluation board. This means all PCB losses and SMA connector losses are included.

5.1 Noise Figure

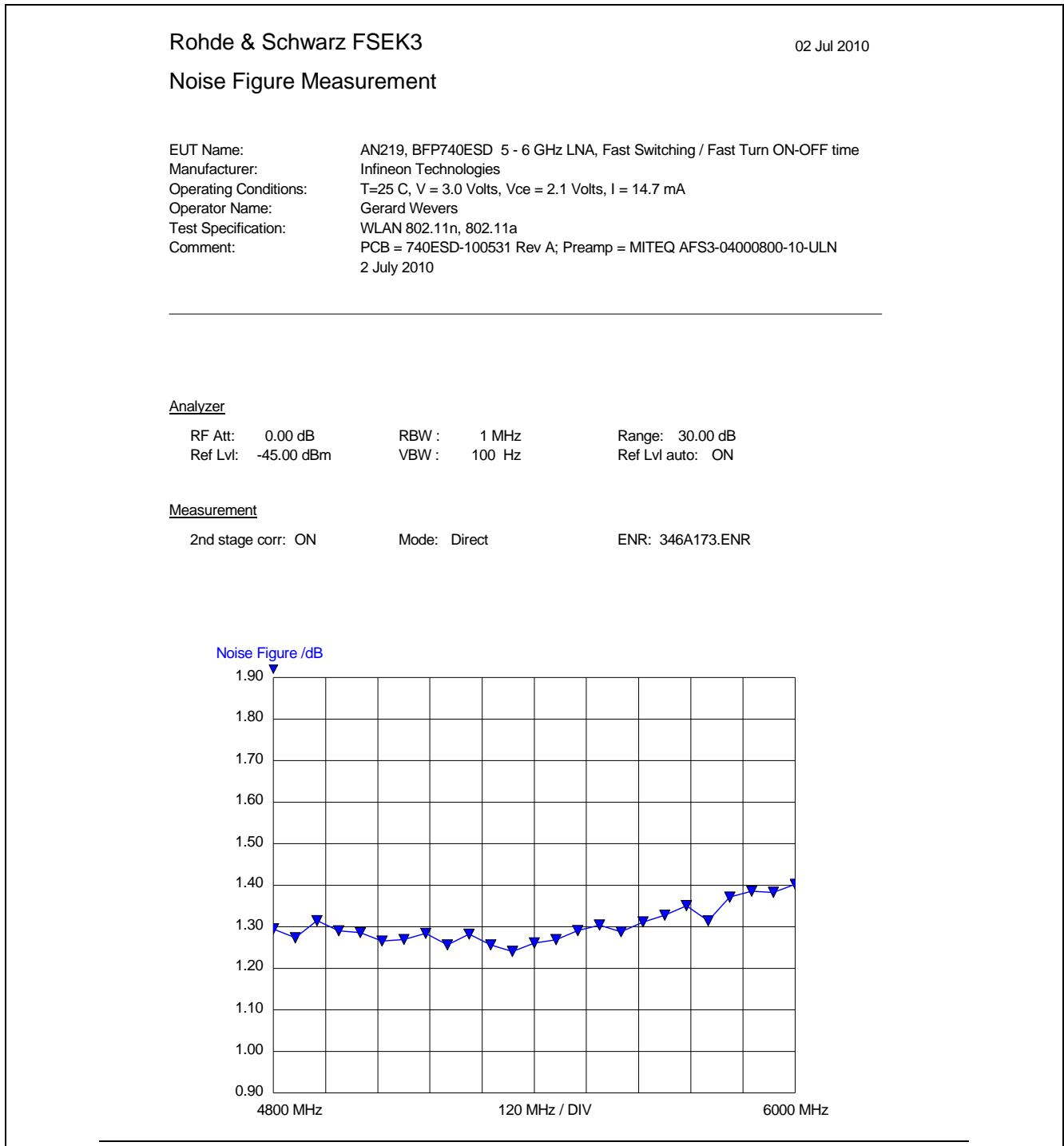


Figure 2 Noise Figure Plot, from Rohde and Schwarz FSEK3 + FSEM30

Table 3 Noise Figure, Tabular Data¹

Frequency / MHz	NF / dB	Noise Temperature / K
4800	1.29	100.7
4850	1.27	98.8
4900	1.31	102.5
4950	1.29	100.3
5000	1.29	100
5050	1.27	98.1
5100	1.27	98.5
5150	1.28	99.8
5200	1.26	97.3
5250	1.28	99.6
5300	1.26	97.3
5350	1.24	95.9
5400	1.26	97.7
5450	1.27	98.4
5500	1.29	100.4
5550	1.3	101.6
5600	1.29	100.1
5650	1.31	102.2
5700	1.33	103.7
5750	1.35	105.8
5800	1.31	102.5
5850	1.37	107.7
5900	1.39	109
5950	1.38	108.8
6000	1.4	110.5

¹ Taken with Rohde & Schwarz FSEM30 + FSEK3; System Preamplifier: MITEQ 4-8 GHz LNA

5.2 1 dB Compression Point

Gain Compression at 5470 MHz, VCC = +3.0 V, I = 14.2mA, VCE = 2.1V, T = 25°C:

Rohde & Schwarz ZVB20 Vector Network Analyzer is set up to sweep input power to LNA at a fixed frequency of 5470 MHz. X-axis of VNA screen-shot below shows input power to LNA being swept from -30 to -5 dBm. ZVB20 output power over sweep range is calibrated at end of test cable (reference plane at input SMA connector to Amplifier Under Test) with Rohde & Schwarz NRP-Z21 power sensor.

Input 1 dB compression point = -6.4 dBm

Output 1dB compression point = -6.4 + (Gain – 1dB) = -6.4 dBm + 14.5 dB = +8.1dBm

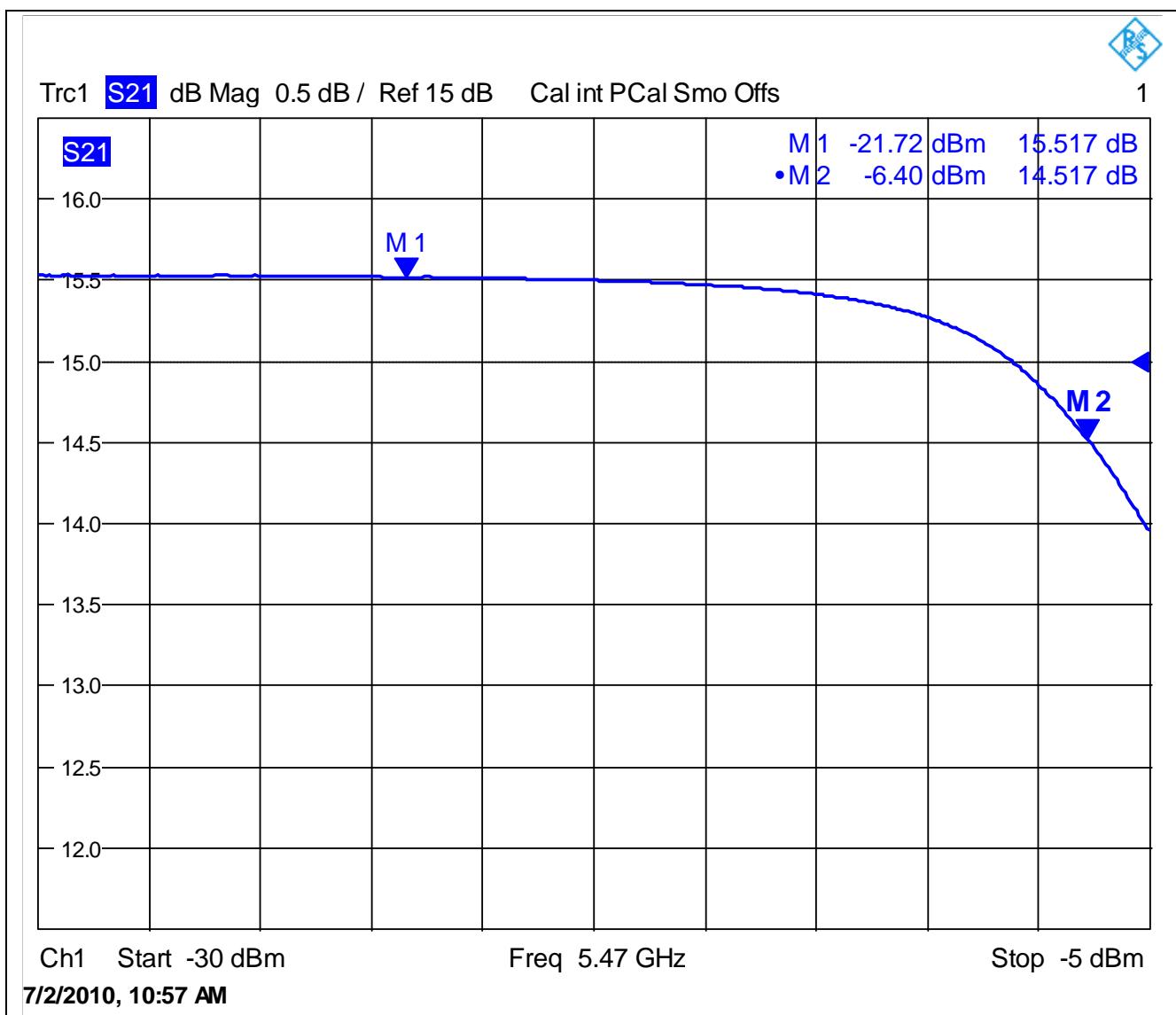


Figure 3 Input 1 dB Compression Point

5.3 Gain

Input / Output Matching Circuits of LNA reduce gain in 2.4 – 2.5 GHz band

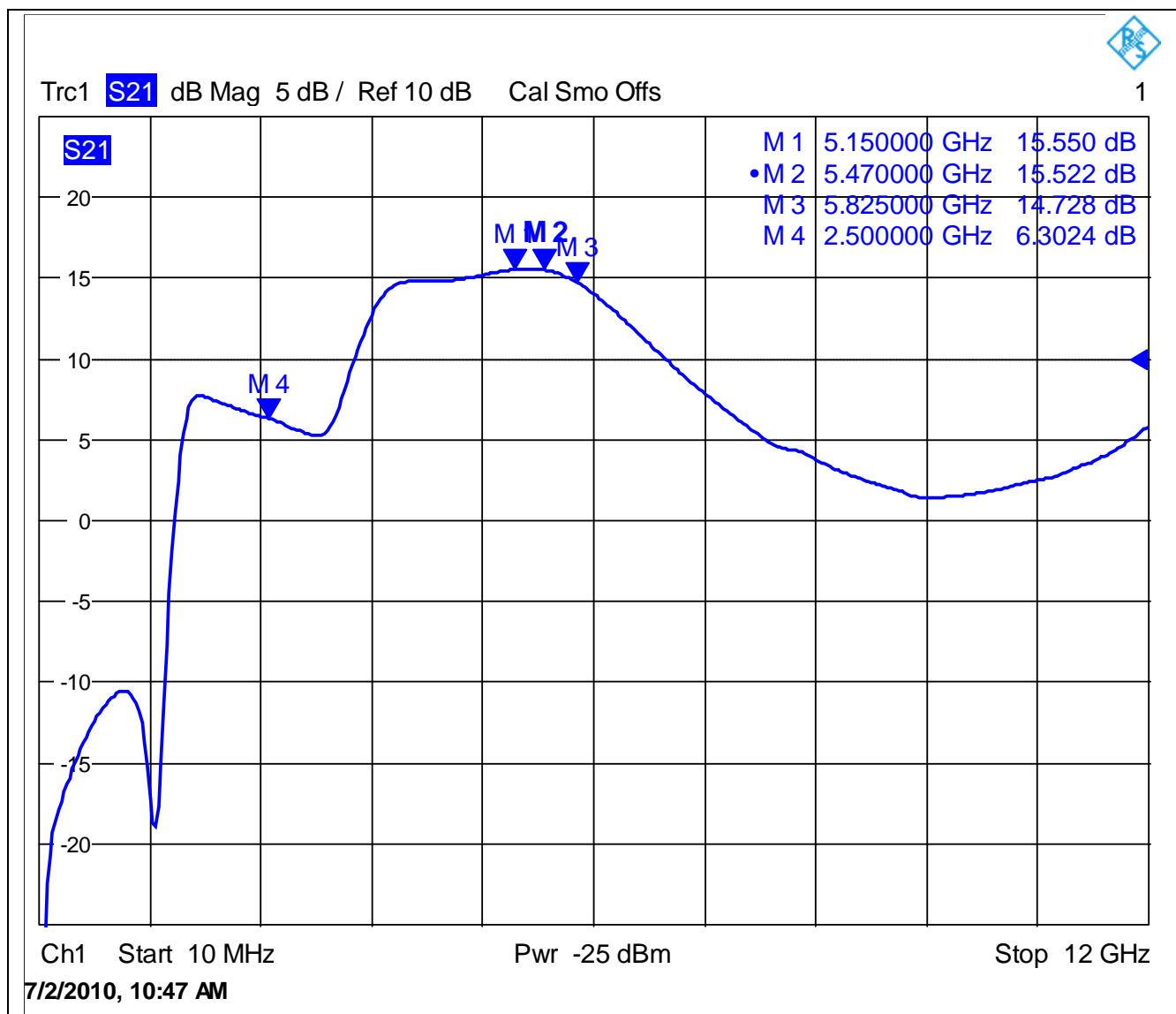


Figure 4 Forward Gain

5.4 Input Return Loss

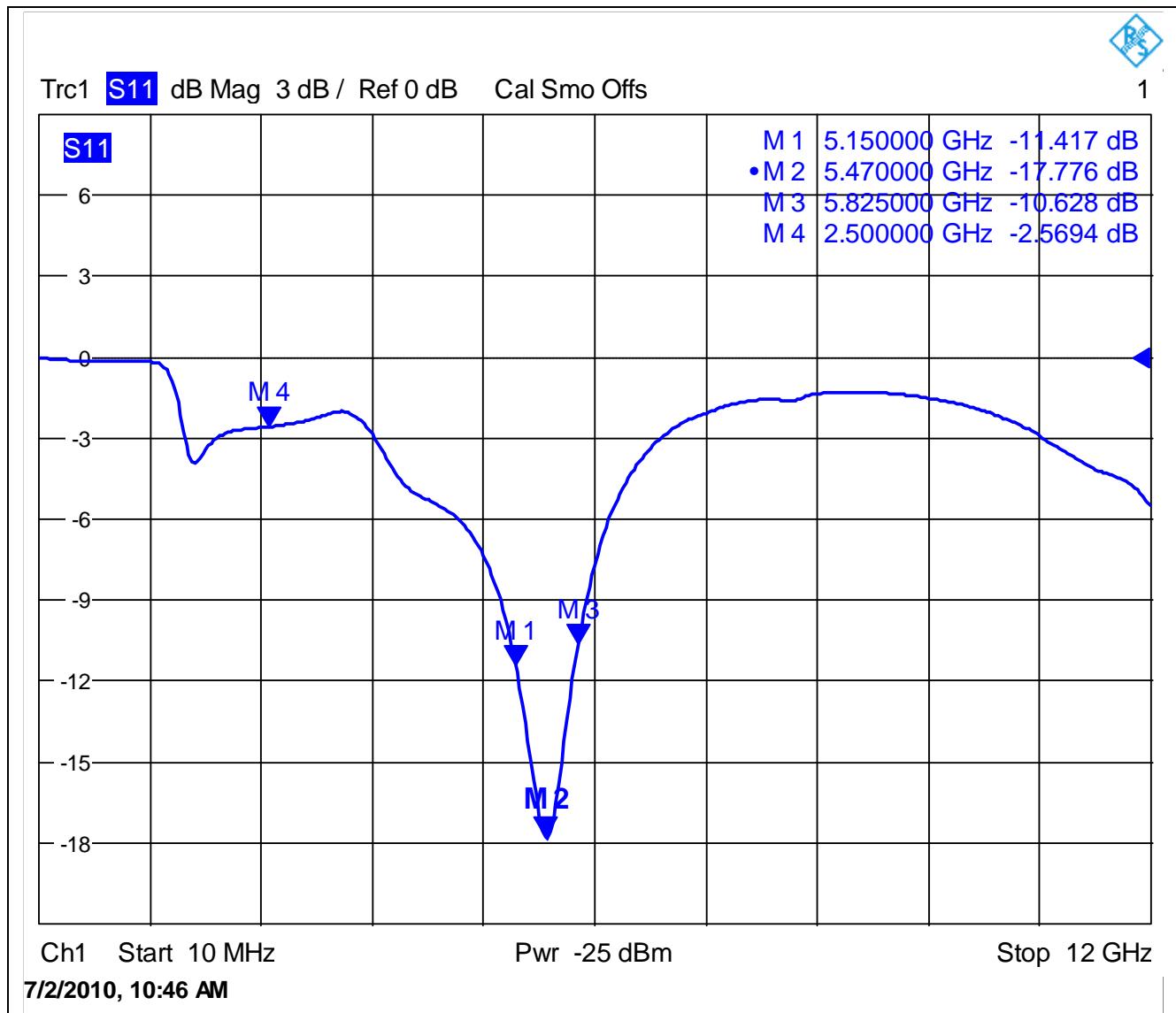


Figure 5 Input Return Loss in dB

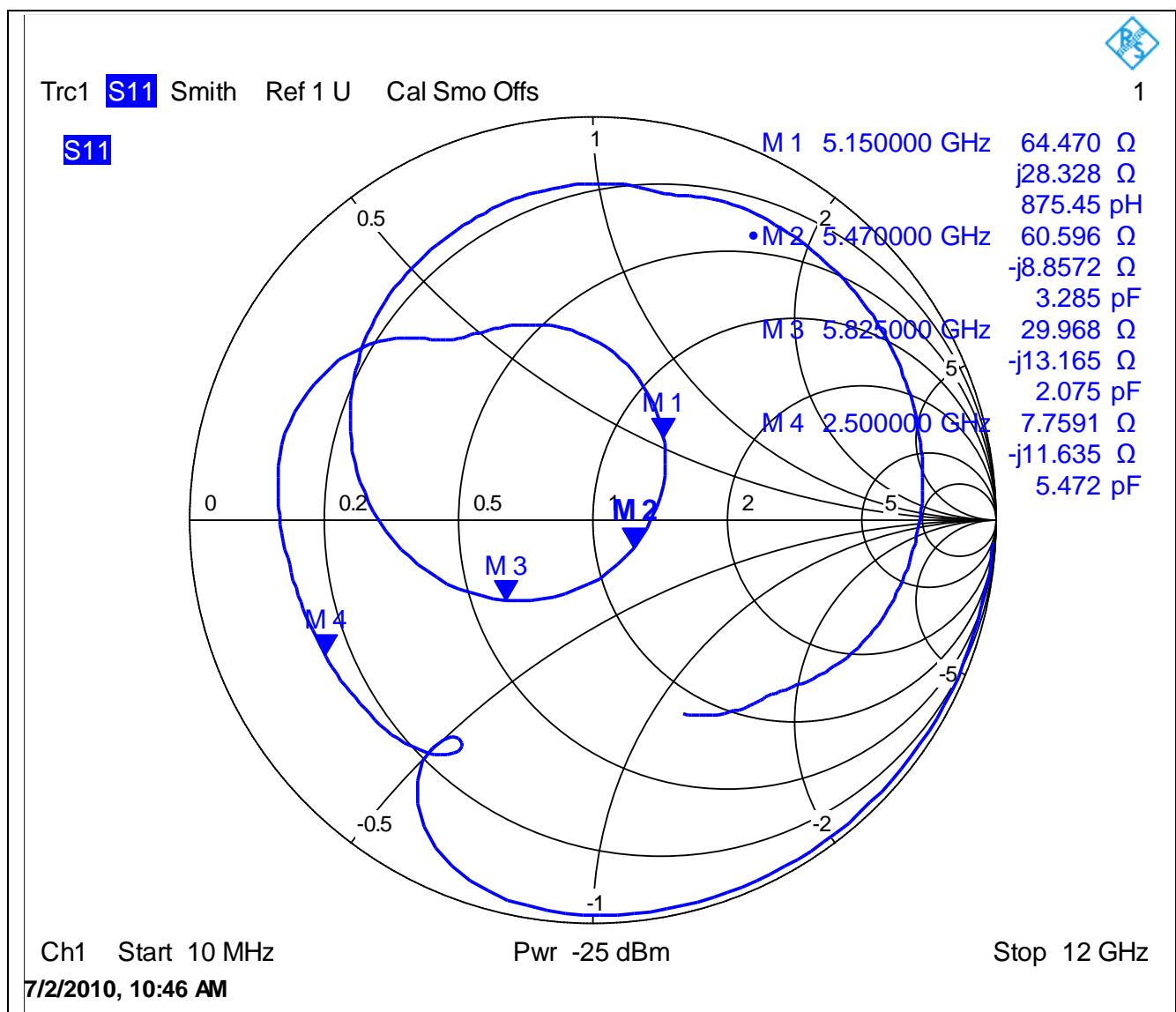


Figure 6 Input Return Loss, Smith Chart

5.5 Output Return Loss

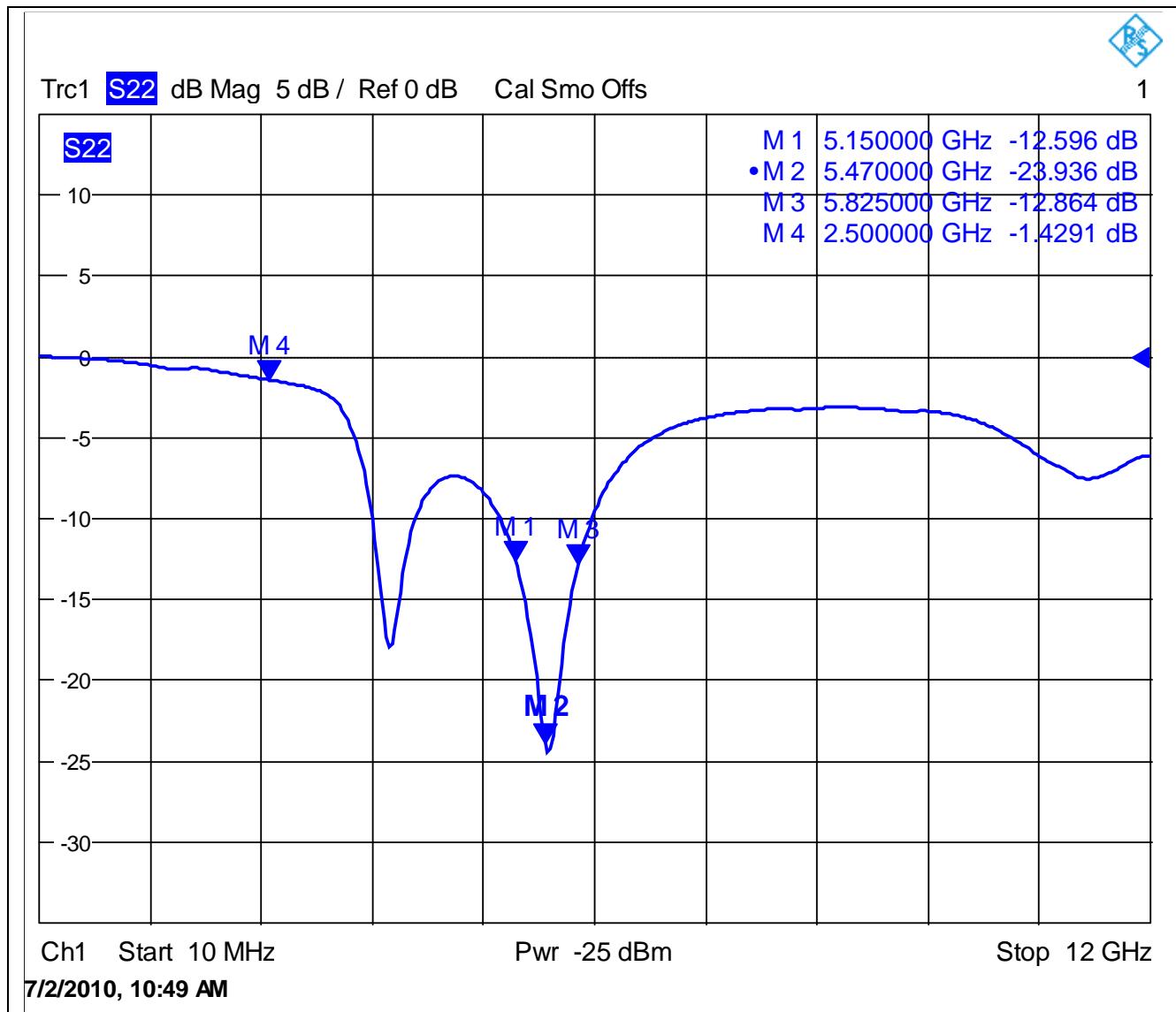


Figure 7 Output Return Loss in dB

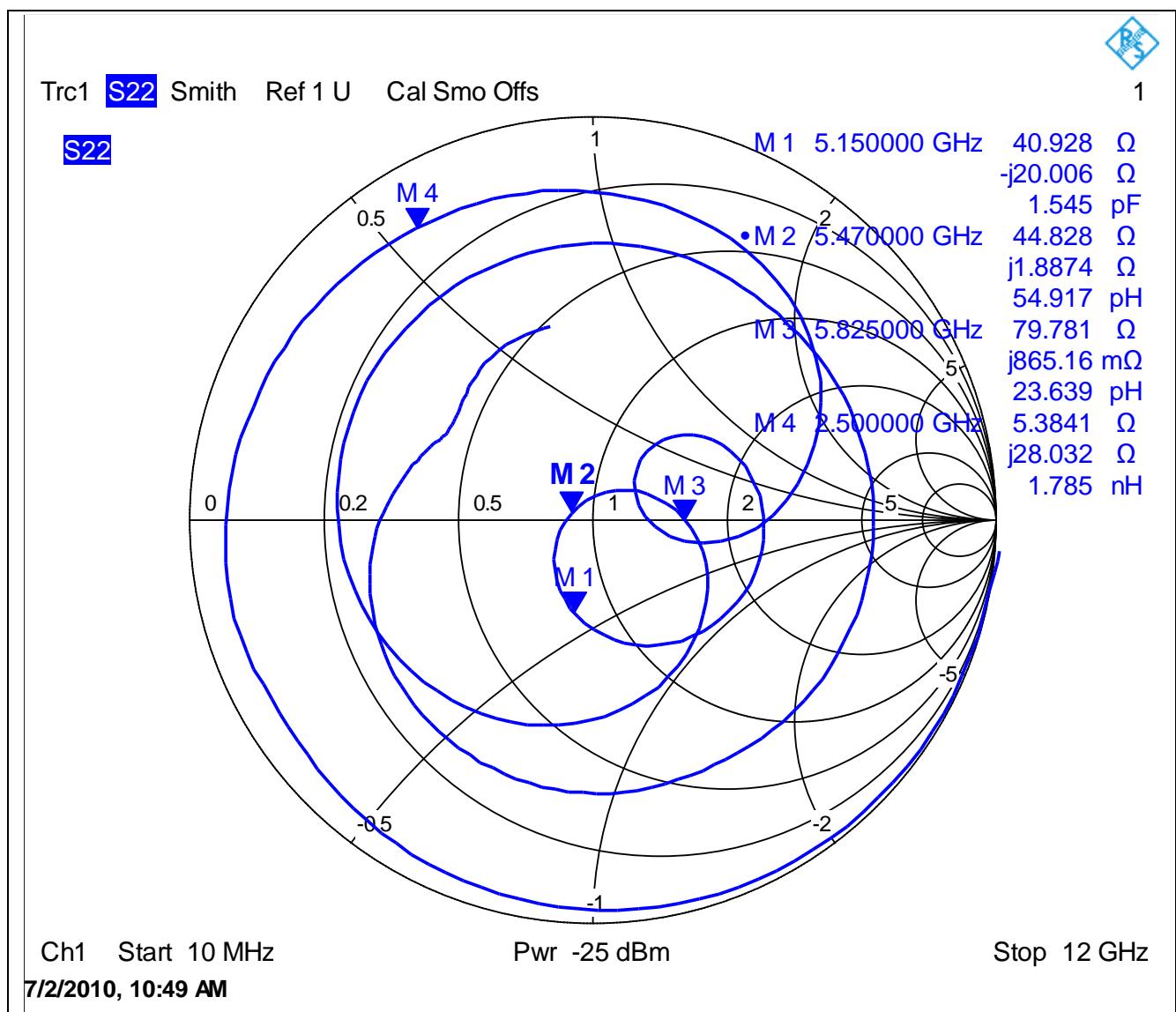


Figure 8 Output Return Loss, Smith Chart

5.6 Reverse Isolation

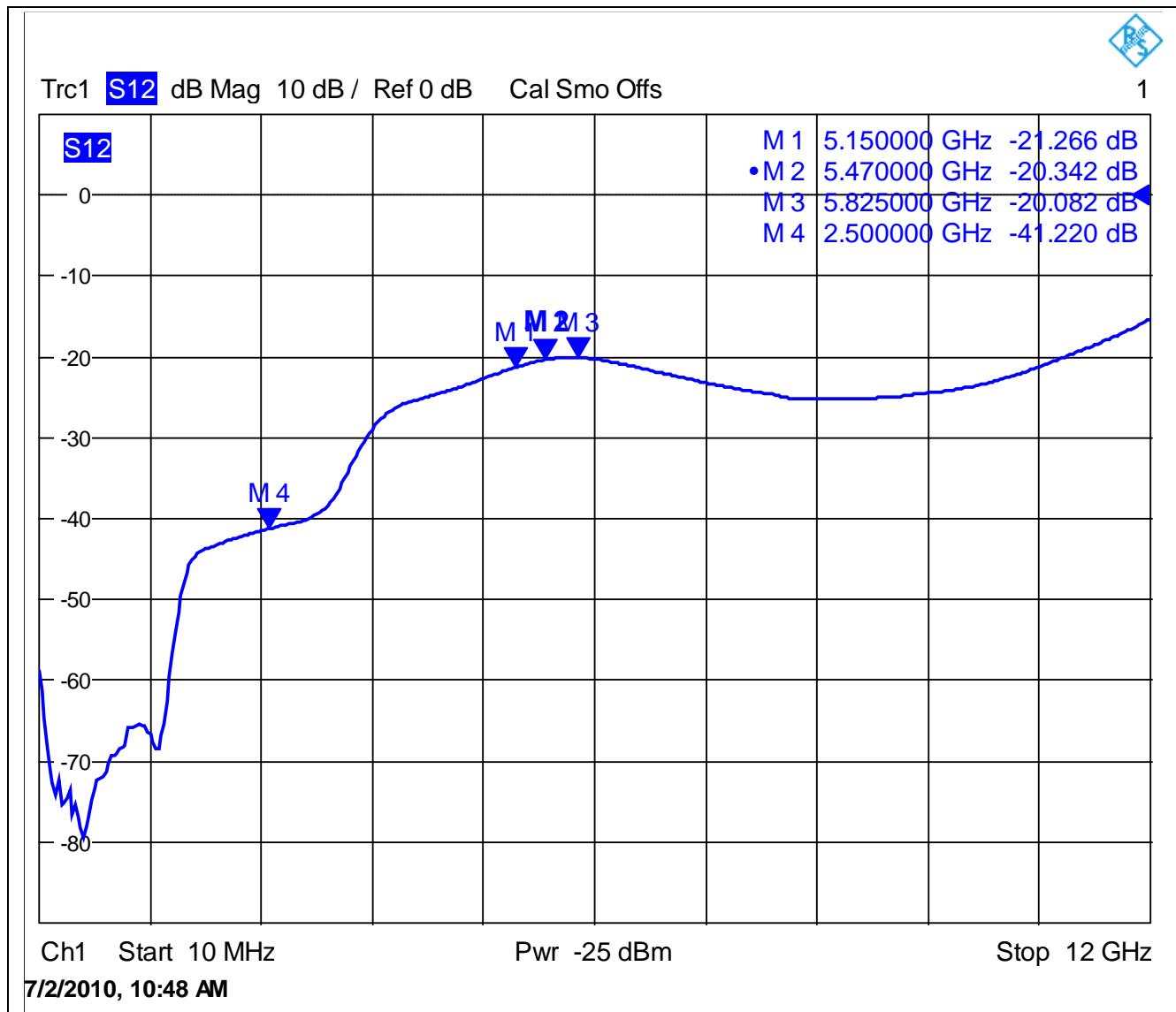


Figure 9 Reverse Isolation

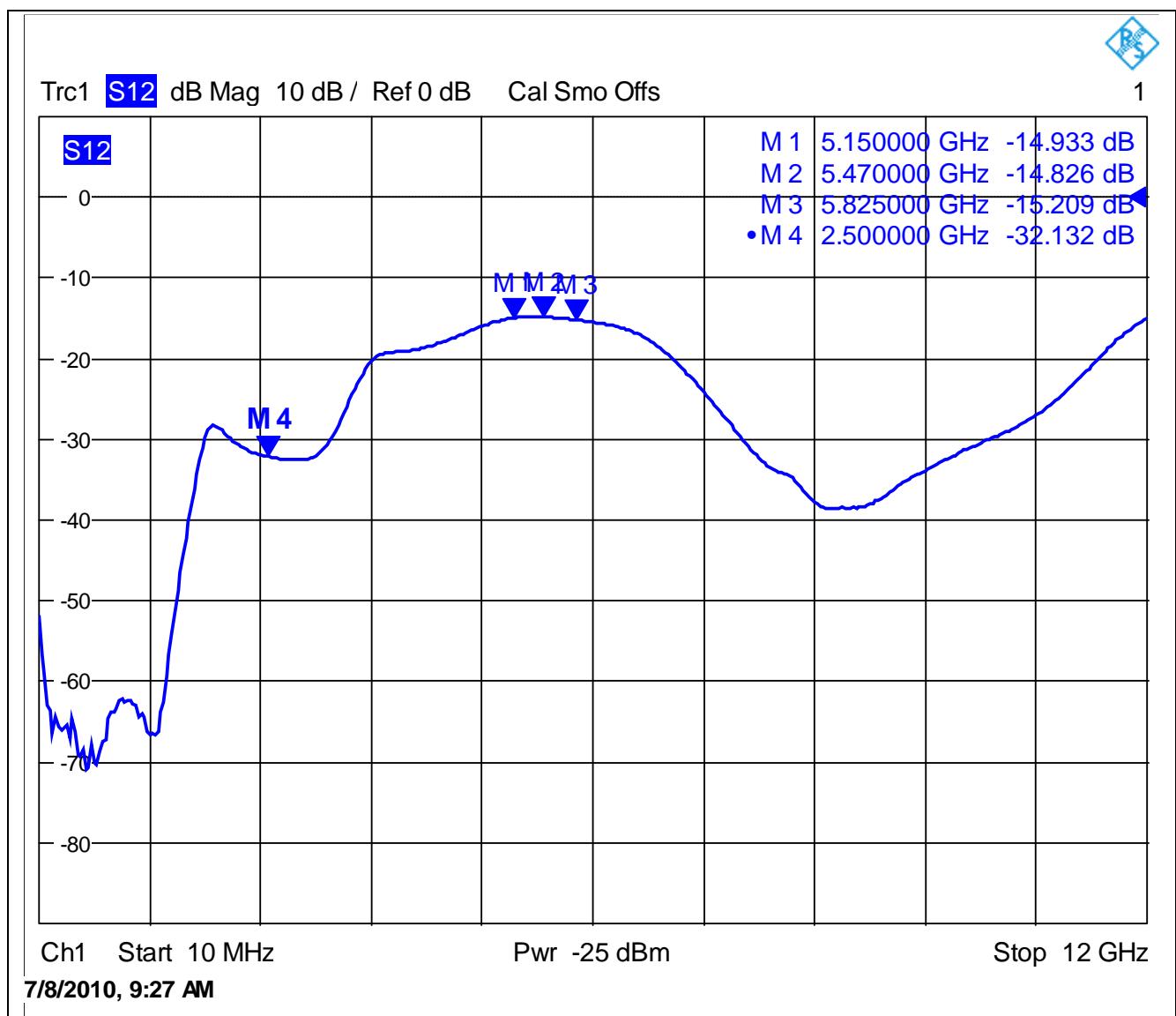


Figure 10 Reverse Isolation, Amplifier DC Power turned off

5.7 Amplifier Stability

Rohde and Schwarz ZVB Network Analyzer calculates and plots stability factor “ μ_1 ” of the BFP740FESD amplifier in real time. Stability Factor μ_1 is defined as follows¹:

$$\mu_1 = \frac{1 - |S_{11}|^2}{|S_{22} - S_{11} \cdot \text{det}(S)| + |S_{21}S_{12}|}$$

Figure 11 Definition of Stability Factor μ_1

The necessary and sufficient condition for Unconditional Stability is $\mu_1 > 1.0$. In the plot, $\mu_1 > 1.0$ over 10 MHz – 12 GHz; amplifier is Unconditionally Stable over 10 MHz – 12 GHz frequency range.

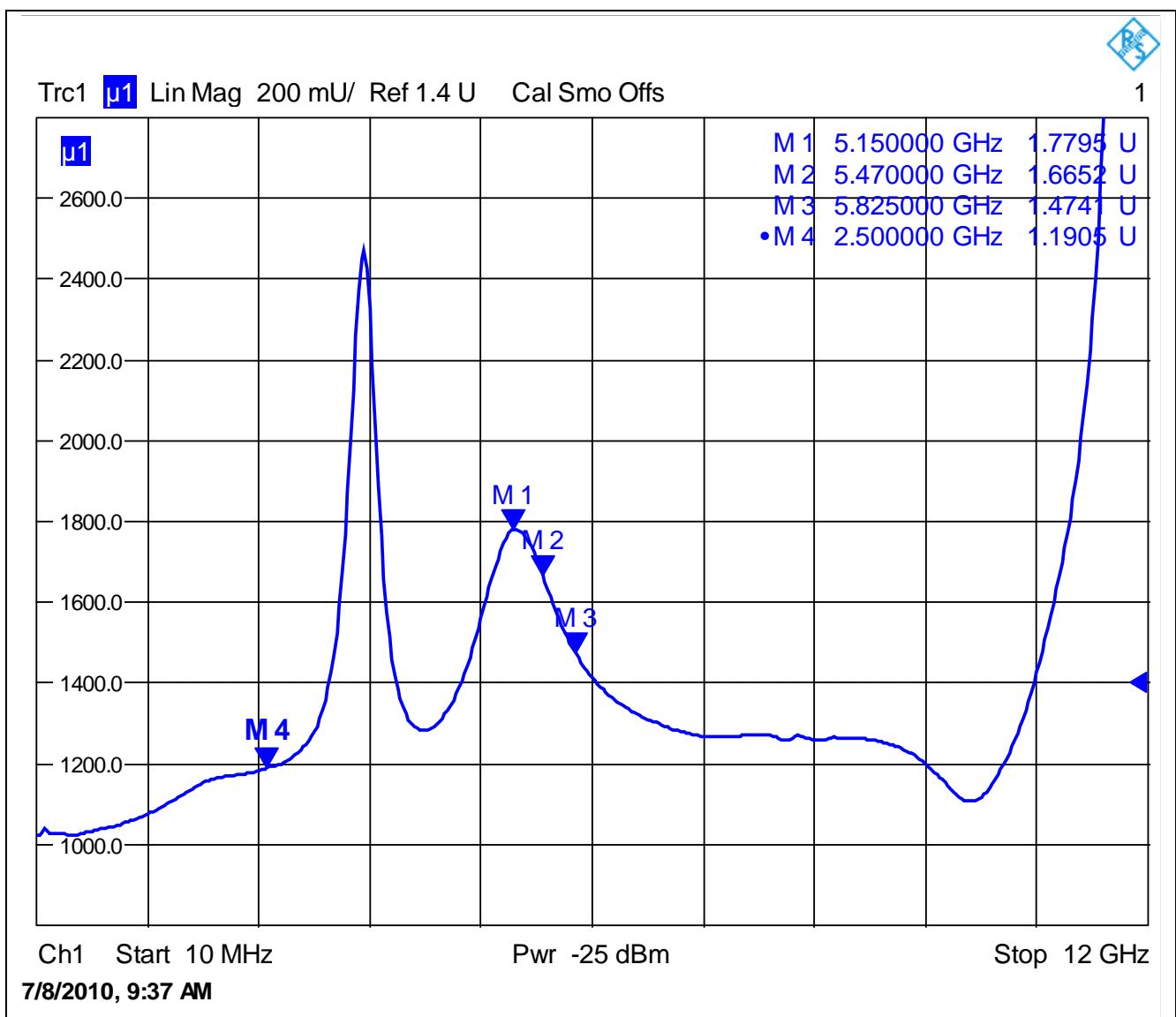


Figure 12 Stability Factor

¹ “Fundamentals of Vector Network Analysis”, Michael Hiebel, 4th edition 2008, pages 175 – 177, ISBN 978-3-939837-06-0

5.8 Third Order Intercept Point

In-Band Third Order Intercept (IIP3) Test.

Input Stimulus: f1=5470 MHz, f2=5471 MHz, -20 dBm each tone.

Input IP3 = -20 + (54.3 / 2) = +7.2 dBm. Output IP3 = +7.2 dBm + 15.5 dB gain = +22.7 dBm.

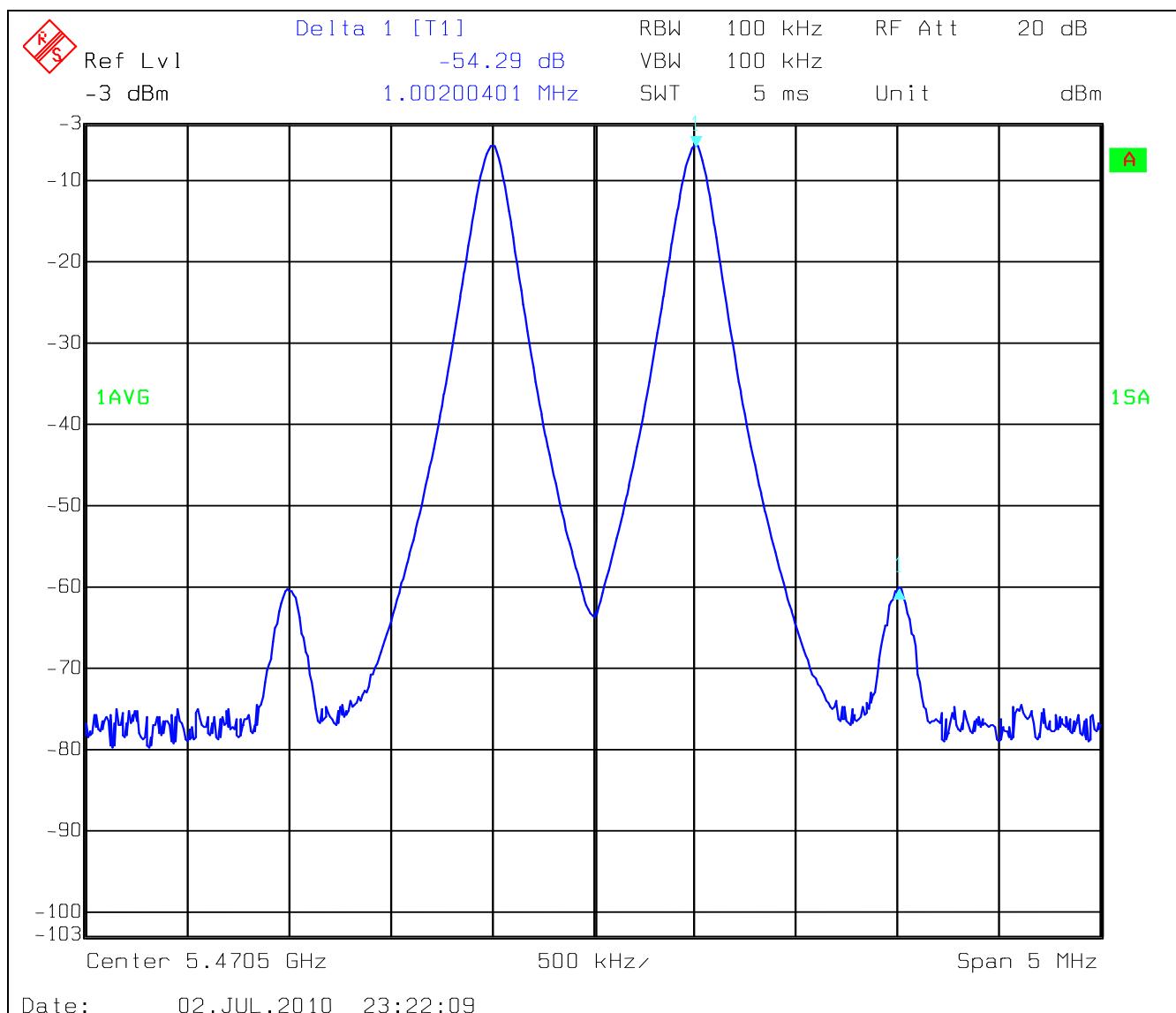


Figure 13 Carrier and Intermodulation Products at LNA's Output

5.9 Turn-On / Turn-Off Time

The amplifier is tested for turn-on / turn-off time. See diagram below. The RF signal generator runs continuously at a power level sufficient to drive the output of the LNA to approximately 0 dBm when the LNA has DC power ON.

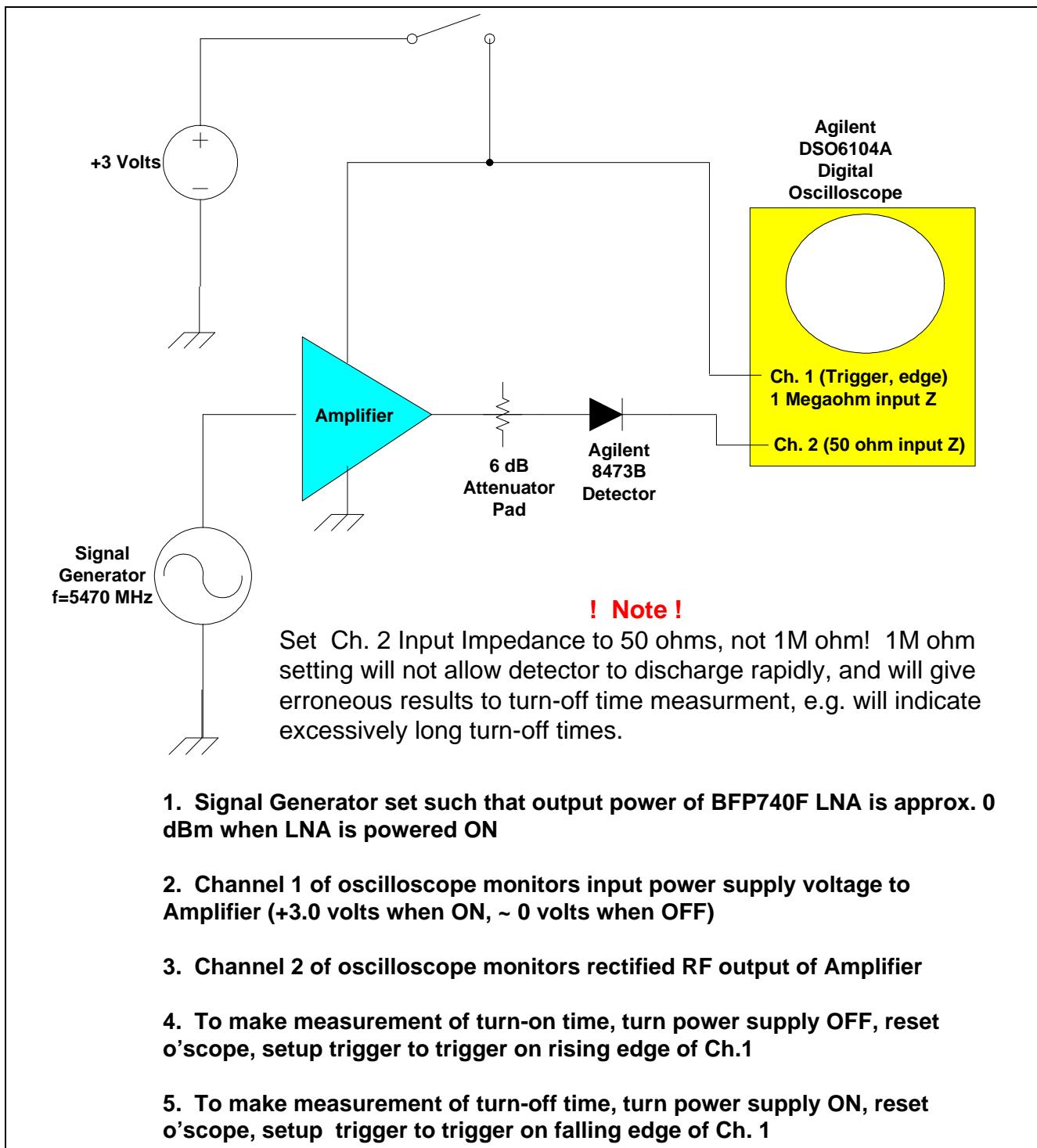


Figure 14 Test setup for Turn-On / Turn-Off measurements

5.9.1 Turn On Time

Refer to oscilloscope screen-shot below. Upper trace (yellow, Channel 1) is the DC power supply turn-on step waveform whereas the lower trace (green, Channel 2) is the rectified RF output signal of the LNA stage. Amplifier turn-on time is approximately 50 ns, or 0.05 ms. Main source of time delay in the LNA turn-on and turn-off events are the R-C time constants formed by $(R3 * C4)$, $[(R2+R3) * C3]$, etc. Charge storage has been minimized in this circuit so as to speed up turn on and turn off times. (Refer to Figure 1).

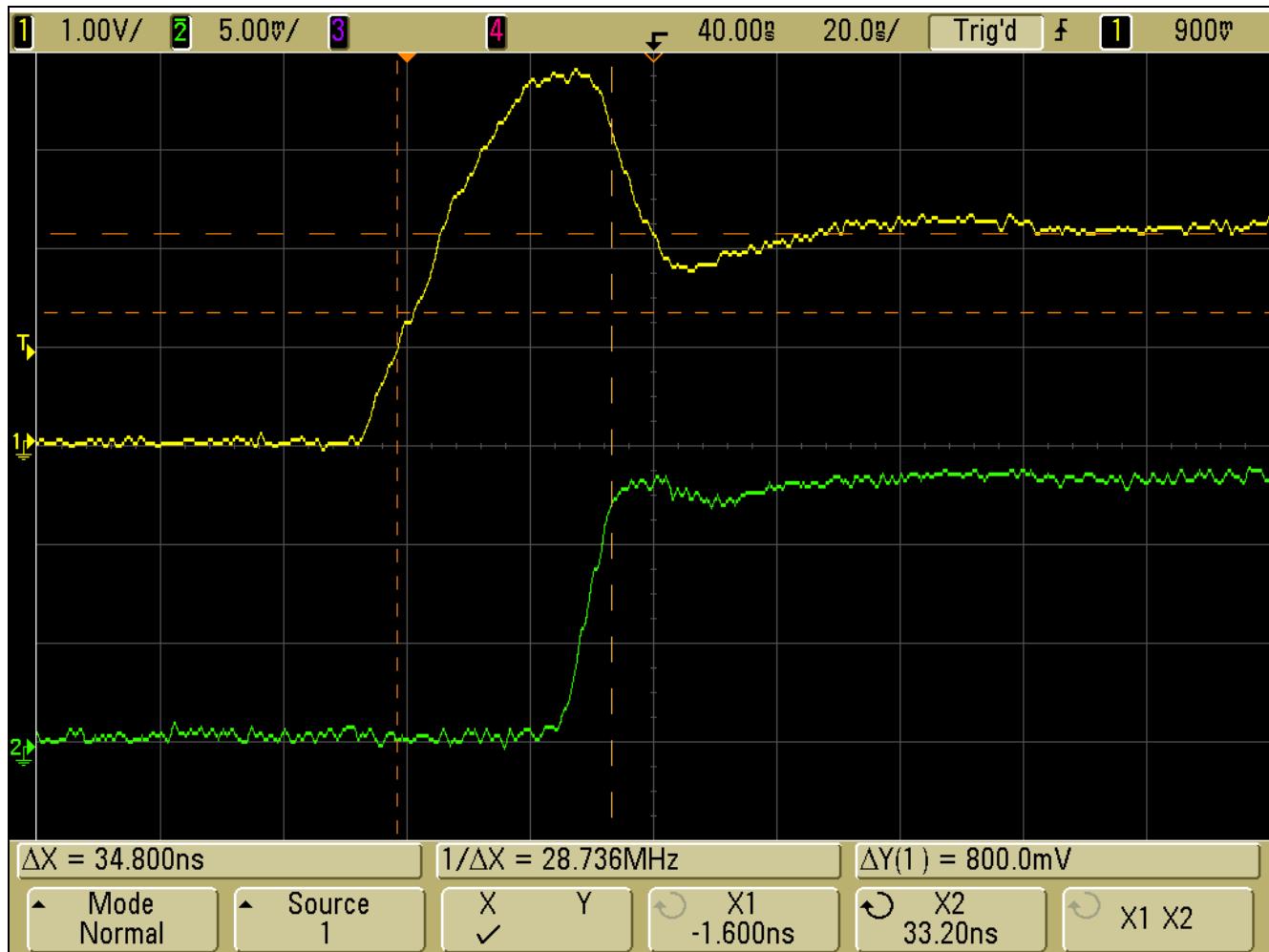


Figure 15 Turn On Time

5.9.2 Turn Off Time

Rectified RF output signal (lower green trace) takes approximately ~ 125ns, or ~0.1ms to settle out after power supply is turned off. Note that input impedance of digital oscilloscope which senses RF Detector Diode output is set to 50Ω , rather than $1\text{ M}\Omega$, to permit RF Detector Diode to rapidly discharge after Amplifier is turned off.

If input impedance of oscilloscope is set to $1\text{ M}\Omega$, the RF Detector will have to discharge through this $1\text{ M}\Omega$ impedance, giving excessively long results for the turn-off time measurement.

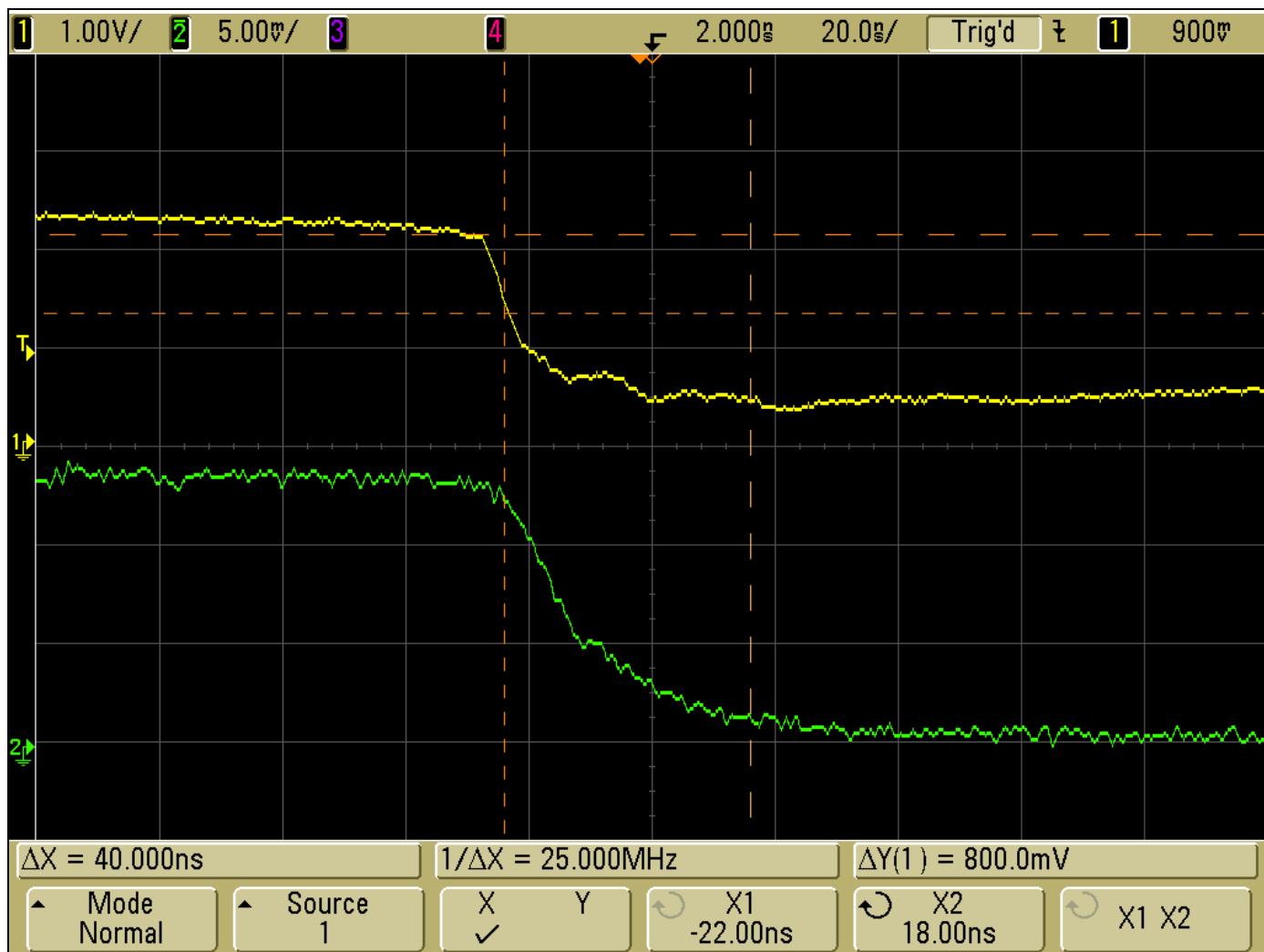


Figure 16 Turn Off time

6 Details of PC Board Construction



Figure 17 View of entire PC Board, Top / Component Side

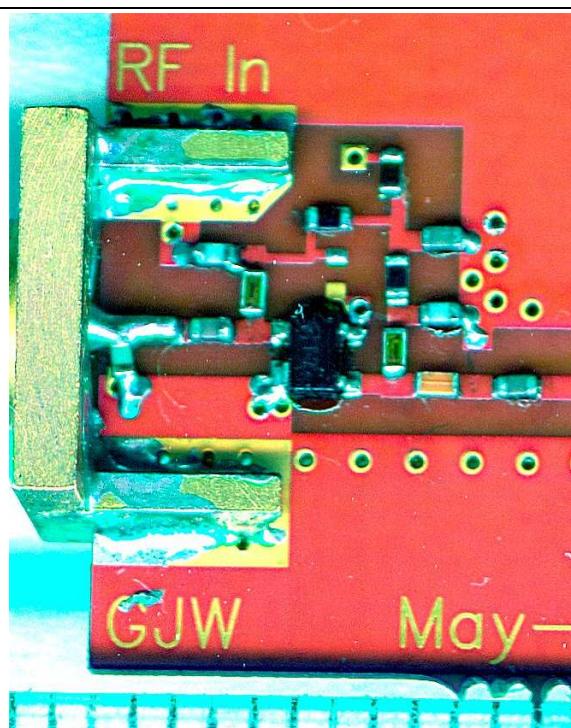


Figure 18 Close-In View of LNA Section

Details of PC Board Construction

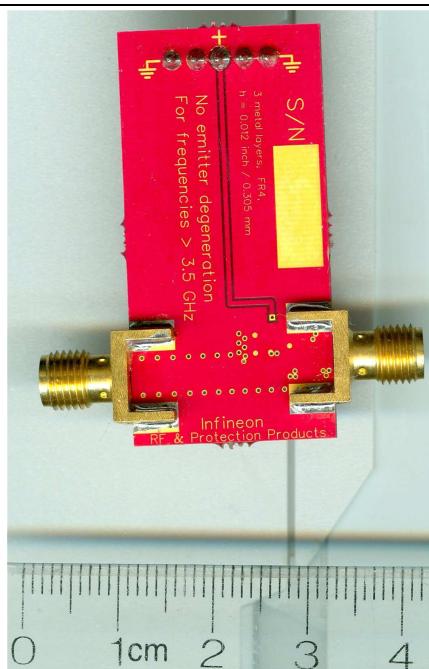


Figure 19 Backside of PCB

PC board is fabricated from standard, low-cost "FR4" glass-epoxy material. A cross-section diagram of the PC board is given below.

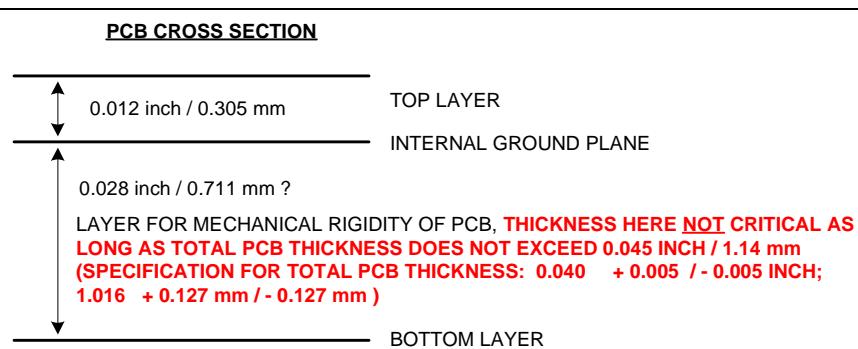


Figure 20 PCB Layer Information

7 SOT343 Package Outline and Foot Print

Dimensions in millimeters. Note maximum package height is 0.59 mm / 0.023 inch

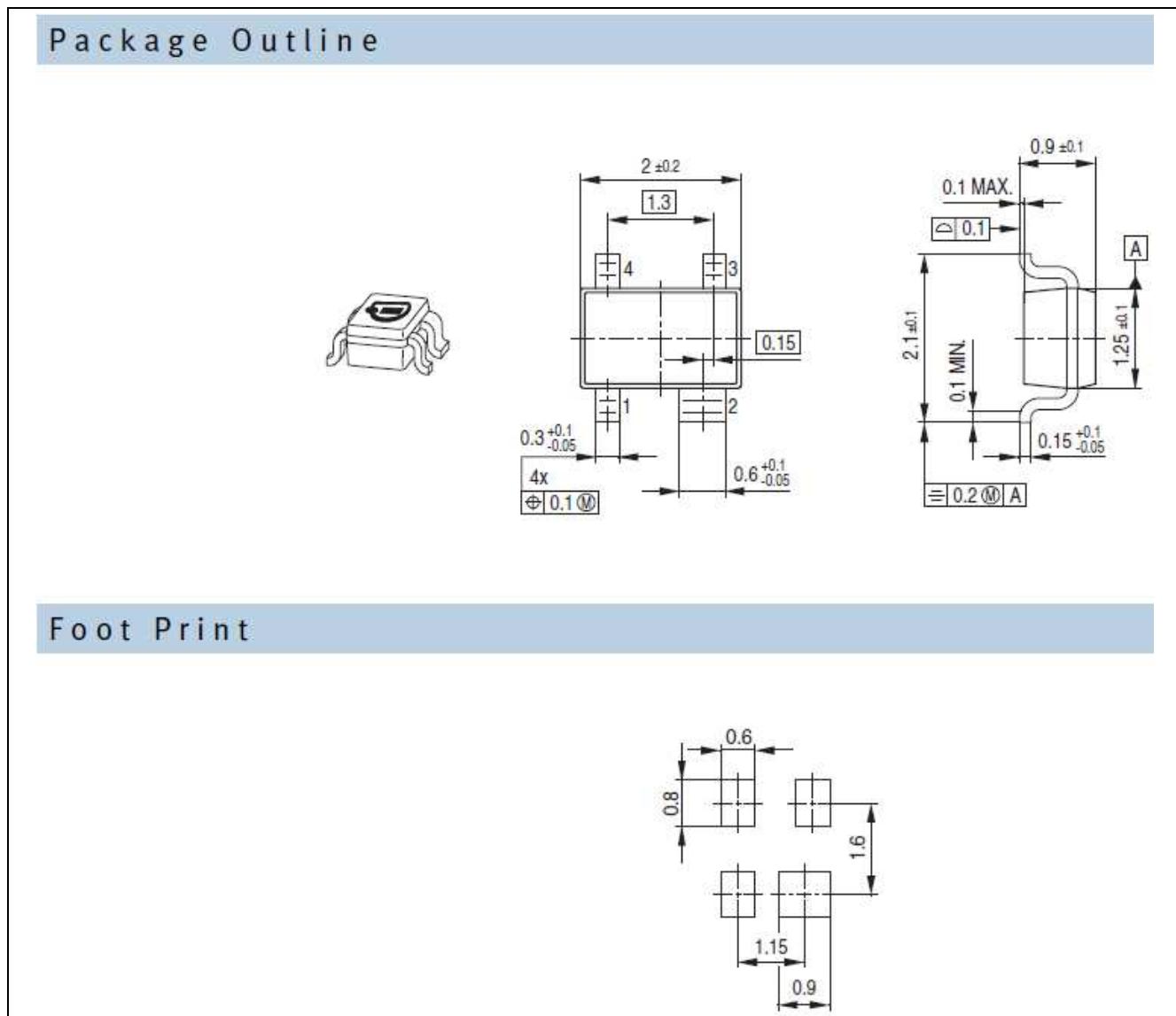


Figure 21 SOT344 package outline and recommended foot print

8 ESD Protection

Electrostatic discharge (ESD) plays an important role when ESD sensitive devices are connected to exposed interfaces or antennas that can be touched by humans. This is usually applicable to low noise amplifiers (LNAs) and therefore LNAs must be properly protected against ESD in order to avoid irreversible damage of the LNA.

For mobile applications low voltage supply and low current consumption is a major issue that requires new technologies with smaller transistor structures. However, the smaller the transistor structure the more sensitive the transistor is to ESD events. Therefore, RF-LNAs based on new front-end technologies have already ESD protection elements integrated on-chip, e.g. BFP740ESD, BFP640FESD, BFP540FESD. These on-chip ESD protection techniques are always a compromise between good ESD protection and RF performance. Integrated RF ESD concepts hardly ever achieve an ESD protection above ± 2 kV according HBM. An on-chip ESD protection of ± 1 kV HBM (component level ESD test JEDEC JESD 22-A115) is quite sufficient to protect the chip from ESD events in the manufacturing environment where stringent measures are taken to prevent electrostatic buildup. However in the field, exposed antennas, for example, always require higher ESD protection levels of at least ± 8 kV up to ± 15 kV. Additional the more stringent system level test according to IEC61000-4-2 is applied. Therefore a special ESD protection becomes mandatory to handle the majority of the ESD current. An ESD protection based on silicon TVS diodes fits perfect to keep the residual ESD stress for the subsequent device as small as possible.

For high frequency applications (2.4GHz and 5GHz WLAN) ESD protection diodes with ultra low line capacitances are required. Infineon offers ultra low clamping voltage and ultra low capacitance, 0.2pF line capacitance, ESD protection diodes in leadless packages of EIA case 0402 (TSLP-2-17) as well as 0201 (TSSLP-2-1):

ESD0P2RF-02LRH / -02LS

The Infineon TVS diode ESD0P2RF has a line capacitance of only 0.2 pF and comes in either a TSLP-2-17 package (1 mm x 0.6 mm x 0.39 mm) or a super small TSSLP-2-1 package (0.62 mm x 0.32 mm x 0.31 mm).

The ESD0P2 ESD diode is a bidirectional TVS diode with a maximum working voltage of ± 5.3 V. It is capable of handling TX power levels of up to +20dBm without influencing the signal integrity, EVM and harmonic generation. Therefore it is well suited for WLAN 2.4GHz and for a lot of 5GHz applications as well.

Authors

Jerry Wevers, Senior Staff Engineer of Business Unit “RF and Protection Devices”

Dietmar Stolz, Staff Engineer of Business Unit “RF and Protection Devices”

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